## TEST SUMMARY FOR ULTRA-FIT WIRE TO BOARD CONNECTOR SYSTEM

## 1.0 SCOPE

This Test Summary covers Ultra-Fit® 3.50 mm pitch wire to board connector systems with gold and tin plating. Receptacles are terminated with 22 to 16 AWG wire using crimp technology.

## 2.0 PRODUCT DESCRIPTION

## 2.1 PRODUCT NAME AND SERIES NUMBER(S)

Series Number Description

172253

Female Crimp Terminal Receptacle Housing 172256/172258 TPA 172264/172268

Vertical Header 17286/172287/172298/172299

Right Angle 172310/172316

## 2.2 DIMENSIONS, MATERIALS, PLATINGS AND MARKINGS

Dimensions, Materials & Plating: See individual sales drawings. (SD-172253-1000, SD-172256-0001. SD-172258-0001. SD-172264-0001. SD-172286-1000. SD-172287-1000. SD-172298-1000, SD-172299-1000, SD-172310-1000, SD-172316-1000, 1722532000, 1722560003, 1722580003, 1722640002)

## 2.3 PRODUCT SPECIFICATION TITLE AND DOCUMENT NUMBER

Product Specification for Ultra-Fit Wire to Board Connector System: PS-172323-0001. Application Specification: AS-172323-0001; 1723230003

## 3.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

## 3.1 TESTING SEQUENCES

Reference Appendix A

## 3.2 OTHER DOCUMENTS AND SPECIFICATIONS

EIA-364-1000.01

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## 4.0 QUALIFICATION

Laboratory conditions and sample selection are in accordance with EIA-364.

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<b>A2</b>	EC No: 639987	ULTRA-	FIT WIRE TO BOA	ARD	<b>1</b> of <b>16</b>		
<b>7 \_</b>	DATE: 06/22/2020	CON	NECTOR SYSTEM	1	1 OT 10		
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## 5.0 ELECTRICAL PERFORMANCE

Group I Temp Life Sequence

Tin - 144 contacts

Results

- 144 Contacts	เกษอนแอ					
Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]	
Low Level Contact Resistance [initial]	Mate connectors. Apply a Max. voltage of 20mV and a current of 100mA (EIA-364-23) Remove wire and traces resistance value.	2 MAX	0.5	0.82	0.63	
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA- 364-09, test method per Sec. 7	7 MAX Δ	-0.18	0.22	0.04	
Thermal Aging [Δ mΩ from initial]	Mate connector, Tin: expose to 240 hours at 105°C. Gold: expose to 1000 hours at 120°C Per EIA-364-17 Method A	7 MAX Δ	0.17	1.37	0.62	
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	7 ΜΑΧ Δ	0.05	1.37	0.64	

15 μi Au – 144 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply a Max. voltage of 20mV and a current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.47	1.9	1.61
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA-364-09, test method per Sec. 7	3 МАХ Δ	-0.15	0.24	0.03
Thermal Aging [Δ mΩ from initial]	Mate connector, Tin: expose to 240 hours at 105°C. Gold: expose to 1000 hours at 120°C Per EIA-364-17 Method A	3 МАХ Д	-0.2	0.17	-0.02
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	3 ΜΑΧ Δ	0.04	1.88	0.62

## Group I Continued

30 μi Au – 144 contacts

Description	Test Condition	Requirement	Min	Max	Avg	ı
Description	rest Condition	[mΩ]	[mΩ]	[mΩ]	[mΩ]	ı

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	DATE: 06/22/2020	CON	CONNECTOR SYSTEM 2 of 16					
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Low Level Contact Resistance [initial]	Mate connectors. Apply a Max. voltage of 20mV and a current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.55	1.87	1.66
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA-364-09, test method per Sec. 7	3 МАХ Δ	-0.2	0.17	-0.02
Thermal Aging [Δ mΩ from initial]	Mate connector, Tin: expose to 240 hours at 105°C. Gold: expose to 1000 hours at 120°C Per EIA-364-17 Method A	3 МАХ Δ	0.08	1.27	0.64
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	3 ΜΑΧ Δ	0.08	1.24	0.53

## Group II Thermal Shock Sequence

## Tin - 144 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	2 MAX	0.51	0.76	0.6
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA- 364-09, test method per Sec. 7	7 MAX Δ	-0.04	0.2	0.07
Thermal Shock [Δ mΩ from initial]	Mate connector, expose to 10 cycles from -55°C to 85°C Per EIA-364-32 Method A, condition 1	7 ΜΑΧ Δ	0.01	1.03	0.28
Cyclic Temperature and Humidity [Δ mΩ from initial]	Mate connectors; expose to 24 cycles from 25°C/ 80% RH to 65°C/ 50% RH Ramp time: 0.5hr Dwell time: 1hr Per EIA-364-31	7 MAX Δ	0.04	1.13	0.52
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	7 ΜΑΧ Δ	0.08	1.28	0.49

## Group II Thermal Shock Sequence continued.

## 15 μi Au – 144 contacts Description

	Description	Test Condit	[mΩ] $[mΩ]$ $[mΩ]$ $[mΩ]$						
REVISION:	ECR/ECN INFORMA	TION: TITLE:	TES	T SUM	IMARY	FOR		SHEET No.	
<b>A2</b>	EC No: <b>639987</b>		ULTRA-FIT WIRE TO BOARD					<b>3</b> of <b>16</b>	
	DATE: 06/22/2020		CONNECTOR SYSTEM						
DOCUMENT NUMBER:		CREATED	/ REVISED BY:	REVISED BY: CHECKED BY: APPROVED BY			/ED BY:		
1723230001-TS		Di	xon Li	n Li JONNY ZHENG ANSON		N YIN			

Requirement

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Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.53	1.87	1.65
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA- 364-09, test method per Sec. 7	3 МАХ Δ	-0.14	0.2	0.03
Thermal Shock [Δ mΩ from initial]	Mate connector, expose to 10 cycles from -55°C to 85°C Per EIA-364-32 Method A, condition 1	3 МАХ Δ	-0.08	0.53	0.17
Cyclic Temperature and Humidity [Δ mΩ from initial]	Mate connectors; expose to 24 cycles from 25°C/ 80% RH to 65°C/ 50% RH Ramp time: 0.5hr Dwell time: 1hr Per EIA-364-31	3 МАХ Δ	-0.08	0.37	0.17
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	3 ΜΑΧ Δ	-0.07	0.37	0.15

## 30 µi Au – 144 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.54	2.08	1.66
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA- 364-09, test method per Sec. 7	3 МАХ Δ	-0.45	0.15	0.01
Thermal Shock [Δ mΩ from initial]	Mate connector, expose to 10 cycles from -55°C to 85°C Per EIA-364-32 Method A, condition 1	3 МАХ Δ	-0.44	0.42	0.09
Cyclic Temperature and Humidity [Δ mΩ from initial]	Mate connectors; expose to 24 cycles from 25°C/ 80% RH to 65°C/ 50% RH Ramp time: 0.5hr Dwell time: 1hr Per EIA-364-31	3 МАХ Δ	-0.33	0.36	0.1
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	3 МАХ Δ	-0.38	0.36	0.09

## **Group III Vibration Sequence**

## Tin - 144 contacts

	Description	Test Condition	on l	uirement Min mΩ] [mΩ]	Max [mΩ]	Avg [mΩ]	
REVISION:	ECR/ECN INFORMA	TION: TITLE:	TES	T SUMMARY	' FOR		SHEET No.
<b>A2</b>	EC No: <b>639987</b>		ULTRA-	FIT WIRE TO	BOAF	RD	4 -4 46
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Requirement

Min

Max

Avg

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Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	2 MAX	0.51	0.76	0.6
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA- 364-09, test method per Sec. 7	7 ΜΑΧ Δ	1.49	1.96	1.64
Thermal Aging (Preconditioning) [Δ mΩ from initial]	Mate connector, Tin: expose to 120 hours at 105°C. Gold: expose to 120 hours at 105°C Per EIA-364-17 Method A	7 MAX Δ	-0.36	0.3	0.05
Random Vibration [Δ mΩ from initial]	Mate connectors and vibrate per EIA-364-28 Test condition VII-D Tin: 15min each axis. Gold: 1.5hours each axis.	7 ΜΑΧ Δ	0.16	1.76	0.78

15 μi Au – 144 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.49	1.91	1.65
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per FIA.		-0.11	0.35	0.11
Thermal Aging (Preconditioning) [Δ mΩ from initial]	Mate connector, Tin: expose to 120 hours at 105°C. Gold: expose to 120 hours at 105°C Per EIA-364-17 Method A	3 МАХ Д	0.07	0.91	0.5
Random Vibration [Δ mΩ from initial]	Mate connectors and vibrate per EIA-364-28 Test condition VII-D Tin: 15min each axis. Gold: 1.5hours each axis.	3 МАХ Δ	0	0.81	0.35

## Continued Group III Vibration Sequence

## 30 µi Au – 144 contacts

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Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.49	1.96	1.64

<b>A2</b>	EC No: 639987  DATE: 06/22/2020	ULTRA- CON	5 of 16			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:		
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TEST SUMMARY FOR

Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connectors 5 cycles for tin plated and 20 cycles for gold plated connectors at a maximum rate of 10cycles per min. Per EIA- 364-09, test method per Sec. 7	3 ΜΑΧ Δ	-0.36	0.3	0.05
Thermal Aging (Preconditioning) [Δ mΩ from initial]	Mate connector, Tin: expose to 120 hours at 105°C. Gold: expose to 120 hours at 105°C Per EIA-364-17 Method A	3 МАХ Δ	-0.01	0.74	0.33
Random Vibration [Δ mΩ from initial]	Mate connectors and vibrate per EIA-364-28 Test condition VII-D Tin: 15min each axis. Gold: 1.5hours each axis.	3 МАХ Д	-0.03	0.71	0.3

## Group V Thermal Cycling for Fretting

## Tin - 144 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]  Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.		3 MAX	0.52	0.79	0.62
Durability with Environment (Preconditioning) [Δ mΩ from initial]	Mate connector at 5 cycles for tin plated connectors at a maximum rate of 10cycles per min. Per EIA-364-09, test method per Sec. 7		0.22	0.04	
Thermal Aging (Preconditioning) [Δ mΩ from initial]	Mate connector, Tin: expose to 120 hours at 105°C. Per EIA-364-17 Method A  Mate connector, 7 MAX Δ 0.14 3.94		3.94	0.74	
Thermal Cycling [Δ mΩ from initial]	Mate connector, cycle between 15±3°C and 85±3°C as measured on the part. Ramps: 2°C/min Min. Dwell time should insure contacts		0.07	3.88	1.14
Reseating [Δ mΩ from initial]	Unmate/Mate connectors by hand three cycles	7 ΜΑΧ Δ	0.09	3.37	0.88

Group VII Durability - Measure Dielectric Withstand Voltage

Tin - 48 contacts; 15 μi Au – 48 contacts 30 μi Au – 48 contacts

Description	Test Condition	Requirement	Results
Description	rest Condition	[mΩ]	[mΩ]

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	DATE: <b>06/22/2020</b>	CON	CONNECTOR SYSTEM				
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Insulation Resistance	Unmated connectors. Apply 500 VDC between adjacent terminals or ground. Per EIA-364-21	IR > 1000	IR > 1000	
Dielectric Withstanding Voltage	Unmated connectors. Apply 2200 VAC for 1 min. between adjacent terminals. Per EIA-364-20	No breakdown Current leakage < 5 mA	PASS	

## Group VII Durability - Measure Low Level Contact Resistance

## Tin – 144 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	2 MAX	0.5	0.79	0.62
Durability [Δ mΩ from initial]	Manual mate/unmate connector with latch: 25 cycles for tin plated and 200 cycles for gold plated at a maximum rate of 10cycles per min.  Per EIA-364-09	7 MAX Δ	-0.06	0.37	0.12

## 15 μi Au – 144 contacts

Description	Test Condition	Test Condition		Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.44	1.81	1.62
Durability [Δ mΩ from initial]	Manual mate/unmate connector with latch: 25 cycles for tin plated and 200 cycles for gold plated at		-0.81	0.45	0.15

## Group VII Continued.

## 30 µi Au – 144 contacts

REVISION: ECR/ECN INFORMATION: TITLE:

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Low Level Contact Resistance [initial]	Mate connectors. Apply Max. voltage of 20mV and current of 100mA (EIA-364-23) Remove wire and traces resistance value.	3 MAX	1.51	1.86	1.65
Durability [Δ mΩ from initial]	Manual mate/unmate connector with latch: 25 cycles for tin plated and 200 cycles for gold plated at a maximum rate of 10cycles per min.  Per EIA-364-09	3 MAX <b>Δ</b>	-0.1	0.37	0.13

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DOCUMENT	ΓNUMBER:	CREATED / REVISED BY:	CHECKED BY:	<u>APPROV</u>	/ED BY:
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### 6.0 MECHANICAL PERFORMANCE

### 6.1 Connector Mate/Unmate without latch

## Tin 160 Circuits

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Connector Mating Force without Latches			3.71	4.23	3.91
Connector Unmate Force (Latch Disabled)	Un-mate connectors with latch disabled at a rate of 25.4 ±6mm per min. Per EIA-364-37	4 MAX per Circuit	2.98	3.19	3.08

## 15 µi Au 160 Circuits

Description	Test Condition	Req. [N]	Min [N]	Max [N]	Avg [N]
Connector Mating Force without Latches	without   Mate connectors at a rate of 25.4   2		1.64	2.23	1.93
Connector Unmate Force (Latch Disabled)	Un-mate connectors with latch disabled at a rate of 25.4 ±6mm per min. Per EIA-364-37	2.3 MAX per Circuit	1.52	1.97	1.69

## 30 µi Au 160 Circuits

Description	Test Condition	Req. [N]	Min [N]	Max [N]	Avg [N]
Connector Mating Force without Latches	out    Mate connectors at a rate of 25.4   2.8 MAX   +6mm per min Per FIA-364-37   per Circuit		1.84	2.05	1.93
Connector Unmate Force (Latch Disabled)	Un-mate connectors with latch disabled at a rate of 25.4 ±6mm per min. Per EIA-364-37	2.3 MAX per Circuit	1.55	1.82	1.66

### 6.2 Connector Mate/Unmate with latch without terminals: 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Connector Mating Force with Latches and without Terminal	Mate connectors at a rate of 25.4 ±6mm per min. Per EIA-364-37	8 MAX per Connector	4.70	6.52	5.63

## USCAR vibration, class V1, S1,T2 gold 5 Connectors

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]
Vibration per USCAR-2 Class V1, S1, T2	Mate connectors, mounted and vibrate as per USCAR-2 Rev6: 5.4.6 Class V1, S1, T2. Random Duration: 8hrs/axis	3 MAX	1.80	1.95	1.88

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ECR/ECN INFORMATION: TITLE: TEST SUMMARY FOR

A2	DATE: 06/22/2020	_	FIT WIRE TO BOANECTOR SYSTEM		<b>8</b> of <b>16</b>			
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- 6.3 Header Pin Retention Force in the housing
- Header Pin Retention Force in the housing, push from mating side: 10 Pins 6.3.1

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Header Pin Retention Force in the housing Push from mating side	Push at a rate of 25.4 ±6mm per min. Per EIA-364-37	50 MIN per Pin	63.28	84.70	77.84

6.3.2 Header Pin Retention Force in the housing, push from PCB side: 10 Pins

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Header Pin Retention Force in the housing Push from PCB side	Push at a rate of 25.4 ±6mm per min. Per EIA-364-37	10 MIN per Pin	14.60	30.65	21.33

6.4 Header Insertion/Retention into the PCB (Vertical Header with kinked pins 16 circuit, PTH)

Min. hole size 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Header Insertion into the PCB (Vertical Header)  Insert a header at a rate of 25.4±6 mm/min.		35 MAX	16.21	33.91	21.89
Header Retention from the PCB (Vertical Header)	Pull a header at a rate of 25.4±6 mm/min.	1 N MIN	9.14	20.71	13.81

Max. hole size 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Header Insertion into the PCB (Vertical Header with kinked pins)	Insert/Pull a header at a rate of 25.4±6 mm/min.	35 MAX	12.40	19.83	15.47
Header Retention from the PCB (Vertical Header with kinked pins)	Pull a header at a rate of 25.4±6 mm/min.	1 N MIN	7.58	11.53	9.34

Header Insertion/Retention into the PCB (Vertical Header with solder clip) 6.5

Min. hole size 10 Connectors

Description   Test Condition   [N]   [N]   [N]   [N]	Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
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REVISION:	ECR/ECN INFORMATION:	TITLE: TES	T SUMMARY FOR		SHEET No.		
A2	EC No: <b>639987</b>		ULTRA-FIT WIRE TO BOARD				
	DATE: 06/22/2020	CON	<b>9</b> of <b>16</b>				
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:		
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Header Insertion into the PCB (Vertical Header with solder clip)	Insert a header at a rate of 25.4±6 mm/min.	25 MAX	14.70	20.00	17.18
Header Retention from the PCB (Vertical Header with solder clip)	Pull a header at a rate of 25.4±6 mm/min.	1 MIN	6.08	10.07	7.89

## Max. hole size 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Header Insertion into the PCB (Vertical Header with solder clip)	Insert a header at a rate of 25.4±6 mm/min.	25 MAX	14.50	18.31	16.38
Header Retention from the PCB (Vertical Header with solder clip)	Pull a header at a rate of 25.4±6 mm/min.	1 MIN	5.15	9.58	7.60

### R/A Header Insertion/Retention into the PCB (2 crush peg, no terminals) 6.6

## Min. hole size 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
R/A Header Insertion into the PCB (crush pegs)Header with solder clip)	Insert a header at a rate of 25.4±6 mm/min.	35 MAX	10.54	21.23	18.07
R/A Header Retention from the PCB (crush pegs)Header with solder clip)	Pull a header at a rate of 25.4±6 mm/min.	1N MIN	5.05	13.43	9.76

## Max. hole size 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
R/A Header Insertion into the PCB (crush pegs)	Insert a header at a rate of 25.4±6 mm/min.	35 MAX	0.51	1.52	1.15
R/A Header Retention into the PCB (crush pegs)	Insert/Pull a header at a rate of 25.4±6 mm/min.	0.2N MIN	0.41	1.91	1.05

### 6.7 Receptacle Terminal retention force into the housing 10 Terminals / 10 Connectors

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
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<b>A2</b>	EC No: <b>639987</b>	ULTRA-	FIT WIRE TO BOA	ARD	<b>10</b> of <b>16</b>		
	DATE: 06/22/2020	CON	CONNECTOR SYSTEM				
DOCUMENT	NUMBER:	CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:		
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Receptacle Terminal retention force into the housing	Axial pull at a rate of 25.4±6 mm/min.	27 MIN	31.70	36.90	33.70
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### 6.8 Crimped terminal retention force into the housing with TPA 6 Terminals

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Crimped terminal retention force into the housing with TPA	Axial pullout force on the terminal in the housing at a rate of 25±6 mm per min. Per EIA-364-29	27 MIN	33.44	50.19	43.07

### 6.9 Solderability Dip Test 10 Connectors

Description	Test Condition	Requirement	Results
Solderability Dip Test	Per Molex test method: SMES-152	Solder area shall have Min. of 95% solder coverage	PASS

6.10 Solder Clip retention force into the housing: 10 Connectors with 2 Solder Clips each.

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Solder Clip retention into the housing	Axial pullout force on the solder clip at a rate of 25±6 mm per min. Per EIA-364-29	1 MIN	22.99	48.76	33.00

### Receptacle latch retention force: 10 Connectors (16 circuits housing) 6.11

Description	Test Condition	Requirement [N]	Min [N]	Max [N]	Avg [N]
Receptacle latch retention force. Thumb latch yield/strength  Axial pullout force at a rate of 25±6 mm per min. Per EIA-364-29	89 MIN (Locking Tang Option)	102.39	117.10	111.52	
	•	60 MIN (Tangles Option)	70.52	81.53	76.21

### 6.12 Receptacle latch retention force after durability x200 cycles

REVISION: ECR/ECN INFORMATION: TITLE:

Description	Test Condition	Requirement	Min	Max	Avg
Description	rest Condition	[N]	[N]	[N]	[N]

TEST SLIMMARY FOR

<b>A2</b>	EC No: 639987  DATE: 06/22/2020	ULTRA-FIT WIRE TO BOARD CONNECTOR SYSTEM								
DOCUMENT NUMBER: CREATED / REVISED BY: CHE			CHECKED BY:	<u>APPROV</u>	<u>ED BY:</u>					
1723230001-TS		Dixon Li	JONNY ZHENG	ANSON YIN						
TEMPLATE FILENAME: TEST SUMMARY(SIZE A)(V.2),DOC										

Receptacle latch retention force	Axial pullout force at a rate of 25±6 mm per min.	89 MIN (Locking Tang Option)	104.71	119.02	110.93
	Per EIA-364-29	60 MIN (Tangles Option)	68.93	80.42	74.66

### 7.0 Vibration test per USCAR 5.9.6 Class V1, S1, T2

## Tin - 160 contacts

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avg [mΩ]		
Initial		2 MAX	0.5	0.86	0.62		
Connector and/or Terminal Cycling USCAR-2 Rev6: 5.1.7 [Δ mΩ from initial]	Mate and unmate connectors 10 times.	7 MAX <b>Δ</b>	-0.12	0.33	0.08		
Voltage Drop USCAR-2 Rev6: 5.3.2	Cable length 75±3mm.  Mate connectors. Apply DC current 5A per mm2 of conductor cross section.  Measure overall voltage drop across. Substrate measured voltage drop across 150mm length of cable.	NA Conditioning only	NA Conditioning only	NA Conditioning only	NA Conditioning only		
Vibration USCAR-2 Rev6: 5.4.6	Mounting: conductor attachment 100±10mm from the connector body. Conductor sag 10±5mm relative to the plane of attachment points. Mate connectors, mounted and vibrate as per USCAR-2 Rev6: 5.4.6 Class V1, S1, T2. Random Duration: 8hrs/axis	No Discontinuity	No Discontinuity*				
Mechanical Shock USCAR-2 Rev6: 5.4.6 [Δ mΩ from initial]	Mounting: conductor attachment 100±10mm from the connector body. Conductor sag 10±5mm relative to the plane of attachment points. Mate connectors, mounted and subject to shock in each of the 3 axes. 10 shocks per axis, Half Sine Wave, only positive direction, 5~10 ms duration, acceleration 35g.	7 MAX <b>Δ</b>	0.02*	1.53	0.46		

15 μi Au – 60 contacts

Description	Test Condition	Requirement	Min	Max [mΩ]	Avg
	rest Condition	[mΩ]	[mΩ]	wax [m22]	[mΩ]

REVISION:	ECR/ECN INFORMATION:	TITLE: TES	T SUMMARY FOR		SHEET No.				
A2	EC No: <b>639987</b>	_	ULTRA-FIT WIRE TO BOARD						
	DATE: 06/22/2020	CONNECTOR SYSTEM							
DOCUMENT	NUMBER:	CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:					
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	TEMPLATE FILENAME: TEST SLIMMARYISIZE ALV 2) DOC								

Initial		3 MAX	1.52	1.94	1.72		
Connector and/or Terminal Cycling USCAR-2 Rev6: 5.1.7 [Δ mΩ from initial]	Mate and unmate connectors 10 times.	3 MAX <b>Δ</b>	-0.2	0.42	0.04		
Voltage Drop USCAR-2 Rev6: 5.3.2	Cable length 75±3mm. Mate connectors. Apply DC current 5A per mm2 of conductor cross section. Measure overall voltage drop across. Substrate measured voltage drop across 150mm length of cable.	NA Conditioning only	NA Conditioning only	NA Conditioning only	NA Conditioning only		
Vibration USCAR-2 Rev6: 5.4.6	Mounting: conductor attachment 100±10mm from the connector body. Conductor sag 10±5mm relative to the plane of attachment points. Mate connectors, mounted and vibrate as per USCAR-2 Rev6: 5.4.6 Class V1, S1, T2. Random Duration: 8hrs/axis	3 MAX <b>Δ</b> No Discontinuity	No Discontinuity*				
Mechanical Shock USCAR-2 Rev6: 5.4.6 [Δ mΩ from initial]	Mounting: conductor attachment 100±10mm from the connector body. Conductor sag 10±5mm relative to the plane of attachment points. Mate connectors, mounted and subject to shock in each of the 3 axes. 10 shocks per axis, Half Sine Wave, only positive direction, 5~10 ms duration, acceleration 35g.	3 MAX <b>Δ</b> No Discontinuity	-0.23*	0.65*	0.14*		

<sup>\*</sup>Event detector showed no discontinuity (@ 1 micro-seconds) during vibration and shock.

### 8.0 Wire-to-Terminal retention force (30 samples, tinned stranded insulatted wire)

Description	Test Condition	Requirement Min [N]	Min Tested [N]
16 AWG Wire-to- terminal retention force	Axial pullout force at a rate of 25±6 mm per min. Per EIA-364-29	68.4N	97.2N
18 AWG Wire-to- terminal retention force	Axial pullout force at a rate of 25±6 mm per min. Per EIA-364-29	68.4N	118.0N

A2	ECR/ECN INFORMATION:  EC No: 639987	TES		13 of 16					
AZ	2 EC No: 639987 ULTRA-FIT WIRE TO BOARD CONNECTOR SYSTEM								
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	TEMPLATE FILENAME: TEST SUMMARY/SIZE A)(V.2).DOC								

20 AWG Wire-to- terminal retention force	Axial pullout force at a rate of 25±6 mm per min. Per EIA-364-29	57.9N	92.8N
22 AWG Wire-to- terminal retention force	Axial pullout force at a rate of 25±6 mm per min. Per EIA-364-29	35.6N	73.2N

Group S1 – Temperature Rise, tested with UL1061 tinned wire and PCB with 2oz. Copper Traces of 1.8mm width and 3.5mm length.

	Wire to Board Current Rating (Amp Max.) (Tested with TIN plated terminals)													
Connector fully loaded with all circuits powered														
A)A/C )A/ira Ci-a		Circuit Size (Single Row)							Circ	uit Si	ze (D	ual R	ow)	
AWG Wire Size	2	3	4	5	6	7	8	4	6	8	10	12	14	16
16	14						11	12						10
18														
20														
22	9						7	8						5

	Wire to Board Current Rating (Amp Max.) (Tested with GOLD plated terminals)													
Connector fully loaded with all circuits powered														
AWG Wire Size	Circuit Size (Single Row) Circuit Size (Dual Ro						ow)							
	2	3	4	5	6	7	8	4	6	8	10	12	14	16
16	12		11				10	11		9				7
18														
20														
22	8						6	6						5

Group S2 – 18 Day Stability at Current test Resistance (Calculated form Voltage Drop)

Description	Test Condition	Requirement [mΩ]	Min [mΩ]	Max [mΩ]	Avrg [mΩ]
Tin, 16 AWG, 10 samples, 1 thermocouple and 1 voltage drop on each sample	Sequence will be 96 hours @ 12A - 240 hrs with 45 min ON and 15 min OFF - 96 hours @ 12A [total 18 days]	5 MAX	3.42	3.85	3.52
15u Au, 16 AWG, 10 samples, 1 thermocouple and 1 voltage drop on each sample	Sequence will be 96 hours @ 12A - 240 hrs with 45 min ON and 15 min OFF - 96 hours @ 12A [total 18 days]	7 MAX	4.37	4.70	4.74

REVISION: ECR/ECN INFORMATION: TITLE:

A2	EC No: 639987  DATE: 06/22/2020	ULTRA- CON	<b>14</b> of <b>16</b>				
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:			
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**TEST SUMMARY FOR** 

## Appendix A -Test Sequences

Grou	рl	Group II	Group III	Group V	Group VII
Temperature Life		Thermal Shock	Vibration	Thermal Cycling	Durability
144 contacts tin		144 contacts tin	144 contacts tin	144 contacts tin	144 contacts tin
144 contac	cts gold	144 contacts gold	144 contacts gold	(tin plated only)	144 contacts gold
Initial Co	ontact	Initial Contact	Initial Contact	Initial Contact	DWV
Resista	ance	Resistance	Resistance	Resistance	EIA-364-20
EIA-36	4-23	EIA-364-23	EIA-364-23	IA-364-23   EIA-364-23	
				' <u> </u>	
Durab	ility	Durability	Durability		
Tin plated:	5 cycles	Tin plated: 5 cycles	Tin plated: 5 cycles	Durability	Initial Contact
Gold plat	ed: 20	Gold plated: 20	Gold plated: 20	5 cycles	Resistance
cycle	es	cycles	cycles	EIA-364-09	EIA-364-23
EIA-36	4-09	EIA-364-09	EIA-364-09		
Contact Re	esistance	Contact Resistance	Contact Resistance	Contact Resistance	
Thormal	A ain a		Thormal Aging	Thormal Aging	Durability
Thermal		The weed Cheek	Thermal Aging	Thermal Aging	Tin plated: 25
TIN 105°C,		Thermal Shock	105°C, 120 hours	105°C, 120 hours	cycles
GOLD 120°		10 cycles	GOLD 120°C, 1000	GOLD 120°C, 1000	Gold plated: 200
hrs		-55°C and +85°C EIA-364-32	hrs	hrs	cycles EIA-364-09
10 Yrs @		EIA-304-32	10 Yrs @ 65°C	10 Yrs @ 65°C	EIA-364-09
EIA-36	4-17		EIA-364-17	EIA-364-17	
					Contact
Contact Resistance		Contact Resistance	Contact Resistance	Contact Resistance	Resistance
				<u> </u>	
		Cyalia Tamparatura	Random Vibration		
Reseating		Cyclic Temperature and Humidity	EIA-364-28	Thermal Cycling	DWV
3 cyc	les	EIA-364-31	Condition VIID	EIA-364-1000.01	EIA-364-20
		LIA-304-31	Condition viib		
Contact Re	sistance	Contact Resistance	Contact Resistance	Contact Resistance	
			1		Latch Retention
		Reseating		Reseating	Laten Retention
		3 cycles		3 cycles	
		Contact Resistance	]	Contact Resistance	
		001114011110010141100	J	00.11.00.01.01.00	
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**ULTRA-FIT WIRE TO BOARD** 

**CONNECTOR SYSTEM** 

**A2** 

EC No: 639987

DATE: 06/22/2020

TEMPLATE FILENAME: TEST\_SUMMARY[SIZE\_A](V.2).DOC

SHEET No.

**15** of **16** 

# molex

## **TEST SUMMARY**

6.0 Individual Tests

6.1 Connector
Mating / Unmating Force

6.2 Connector
Mating / Unmating with latch
without terminals

6.3 Header Pin Retention Force in the Housing

6.4 Header Insertion/Retention into the PCB (Vertical Header with kinked pins 16 circuit, PTH)

6.5 Header Insertion/Retention into the PCB (Vertical Header with solder clip)

6.6 R/A Header Insertion/Retention into the PCB (crush pegs)

6.7 Receptacle Terminal retention force into the housing 20 Terminals / 4 Connectors

6.8 Crimped terminal retention force into the housing with TPA

6.9 Solderability Dip Test

6.10 Solder Clip retention force into the housing

6.11 Receptacle latch retention force

6.12 Receptacle latch retention force after durability x200 cycles

7.0 USCAR Vibration

Initial Contact Resistance USCAR 5.9.6 Class V1, S1, T2

Connector and/or Terminal Cycling USCAR-2 Rev6: 5.1.7

Voltage Drop USCAR-2 Rev6: 5.3.2

Vibration USCAR-2 Rev6: 5.4.6

Mechanical Shock USCAR-2 Rev6: 5.4.6

Dry Circuit Resistance

8.0 Wire-to-Terminal retention force

REVISION:

**ECR/ECN INFORMATION:** 

EC No: **639987** 

DATE: 06/22/2020

TEST SUMMARY FOR
ULTRA-FIT WIRE TO BOARD
CONNECTOR SYSTEM

SHEET No.

**16** of **16** 

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